

<b>Notice of References Cited</b>	Application/Control No. 10/559,497		Applicant(s)/Patent Under Reexamination FUJII, TAKEHIRO	
	Examiner JAE LEE		Art Unit 2895	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0190770 A1	10-2003	Yeom et al.	438/113
	B	US-			
	C	US-			
	D	US-			
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